Laboratory 3: Configurable Amplifiers Using Small-Signal MOS Resistors Preliminary Exercises

This lab focuses on the use of MOS transistors as voltage-controlled variable resistors. In the lab, we will specifically demonstrate a gain-controllable (i.e., configurable) inverting amplifier and a bandwidth-controllable lowpass filter using op amps, resistors, capacitors, and a discrete MOS transistor.

The preliminary exercises in this section aim to prepare you for this lab. In completing these exercises, you should assume an NMOS transistor with the following parameters:

Transconductance Parameter, $K_n = \mu_n C_{ox}(W/L)$:	471 μA/V ²
Nominal Threshold Voltage, Vto:	1.4 V
Surface Potential, 2¢ _f :	0.66V
Body Effect Parameter, γ:	$0.49V^{1/2}$

Other device parameters can be found in the 'cd4007ub.mod' file online, which is a SPICE model.

1. Gain-Controllable Amplifier

(a) For the MOS transistor circuit shown in Fig. PL3.1(a) below, calculate and tabulate (using the *Results Sheet for Preliminary Exercises*) the values of the small-signal resistance R_{MOS} from drain to source for values of control voltage V_C ranging from 0V to 10V, in steps of 1V. Then, plot your values of R_{MOS} versus V_C on a graph. Again, assume the MOS device parameters given at the beginning of this pre-lab.



(b) For the inverting amplifier circuit shown in Fig. PL3.1(b) (which uses an op amp defined by 'lm741.mod' and an MOS transistor with parameters as in the beginning of this pre-lab defined by 'cd4007ub.mod'), calculate and tabulate (using the *Results Sheet for Preliminary Exercises*) the gain V₀/V_i of this amplifier for values of control voltage V_C ranging from 0V to 10V, in steps of 1V. Then, plot the gain versus V_C on a graph. [Hint: Be careful when determining gain at V_C=0V.]

Assume for this pre-lab that the MOS transistors have zero leakage currents.



(c) Calculate and tabulate (using the *Results Sheet for Preliminary Exercises*) the 3dB bandwidth of the amplifier for values of V_C ranging from 2V to 10V, in steps of 1V. Use SPICE to generate Bode plots for this amplifier, for values of V_C ranging from 1V to 10V. (Plot all curves on the same graph.)

2. Bandwidth-Controlled (Unity-Gain) Filter

- (a) For the filter circuit shown in Fig. PL3.2(a), the op amp uses the model given in 'lm741.mod', and the MOS transistors M_1 and M_2 use the model given at the beginning of this pre-lab and in 'cd4007ub.mod'. Assuming for now that M_1 and M_2 are identical, calculate and tabulate (using the *Results Sheet for Preliminary Exercises*) the 3dB bandwidth of the filter for values of control voltage V_C from 2V to 10V, in steps of 1V.
- (b) Using SPICE, generate Bode plots (all on the same graph) for the circuit of Fig. PL3.2(a) for values of V_C from 2V to 10V, in steps of 1V. Use the SPICE model 'cd4007ub.mod' for each NMOS transistor and use the model in 'lm741.mod' for the op amp.
- (c) Suppose that due to fabrication mismatches, the channel length of M_1 was 10% larger than that of M_2 (everything else identical). What then is the passband gain of this filter?
- (d) Suppose that due to fabrication mismatches, the threshold voltage V_{t1} of M_1 was 20% larger than that of M_2 (everything else identical). Calculate and tabulate (using the *Results Sheet for Preliminary Exercises*) the gain V_0/V_i of the filter for control voltage V_C values from 2V to 10V, in steps of 1V. Plot the gain V_0/V_i versus V_C on a graph.



Helpful Hints for SPICE Simulation

Some notes on creating a MOSFET instance for this lab:

- (1) For the NMOS transistor, you should use the model file on the course website, 'cd4007.mod'.
- (2) To use an NMOS transistor in your netlist, you must first include the model file using a .include statement:

.include <path_to_model_file>

(3) Then, to create an instance of the MOSFET use the following code:

M<name> <drain> <gate> <source> <model_name> (W=<value> L=<value>)

Replace <name> with the desired name of your NMOS instance and <model_name> with the name of the NMOS model, which is defined within 'cd4007.mod'. For the CD4007UB the W is 42 μ m and L is 10 μ m.

(4) To run a nested DC sweep (i.e., to sweep two sources in the same simulation), the syntax is very similar to the standard DC sweep:

.dc <source1> <start1> <stop1> <source2> <start2> <stop2> <step2>

Note that in this analysis, <source1> is swept and <source2> is stepped.

Laboratory 3: Configurable Amplifiers Using Small-Signal MOS Resistors Results Sheet for Preliminary Exercises

1. Gain-Controllable Amplifier

V _C [V]	(a) R _{MOS}	(b) Gain, V_o/V_i	(c) 3dB Bandwidth
0			
1			
2			
3			
4			
5			
6			
7			
8			
9			
10			

Table PLR3.1. Gain-Controllable	Amplifier Characteristics
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Attach the necessary annotated plots for parts (a), (b), and (c).

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2. Bandwidth-Controlled (Unity-Gain) Filter

V _C [V]	(a) 3dB Bandwidth	(d) Gain, V_o/V_i
2		
3		
4		
5		
6		
7		
8		
9		
10		

Table PLR3.2. Bandwidth-Controllable Amplifier Characteristics

(a) Fill in the table above.

- (b) Attach annotated SPICE plot.
- (c) Gain, $V_o/V_i =$
- (d) Fill in the table above and attach the necessary annotated plot.

Laboratory 3: Configurable Amplifiers Using Small-Signal MOS Resistors Laboratory Exercises

INTRODUCTION

Objectives

This lab attempts to illustrate the small-signal operation of a nonlinear device by demonstrating a gain-controllable inverting amplifier and bandwidth-controllable lowpass filter using a small-signal MOS resistor.

Summary of Procedures

- Using the HP 4155B, take sufficient data to determine the parameters needed to predict the small-signal resistance of two discrete MOS transistors under various gate bias voltages.
- (ii) Build a gain-controllable inverting amplifier using an op amp, a resistor, and one of the discrete MOS transistors measured in (i).
- (iii) Measure the gain and bandwidth of the gain-controllable amplifier under various MOS resistor gate bias voltages.

Materials Required

- HP 4155B Semiconductor Parameter Analyzer
- Proto-board
- Power Supplies
- DMM
- Assorted Resistors
- CD4007UB Transistor DIP

PROCEDURE

1. Characterizing MOS Transistors

[<u>Note</u>: This part need not be done first. If an HP 4155B is not available initially, e.g., due to some of them being down or inoperable, you can do the other parts in the lab first, then characterize the NMOS transistors you used as the last step.]

In this part of the lab, you will again use the HP 4155B Semiconductor Parameter Analyzer, this time to measure the *IV*-characteristics of two NMOS transistors contained within the CD4007UB DIP packages. For your reference, the data sheet (including the pin-out) for the CD4007UB transistor DIP is online. Note that this chip contains both NMOS and PMOS

transistors, as well as an inverter circuit. Be careful to choose two *NMOS transistors*, not PMOS, for this part.

(a) You will need to configure the HP 4155A/B/C for MOS I_D versus V_{DS}/V_{GS} curve measurement. Basically, you will set up the sweeps using the same procedures as in Lab 2, though this time you will configure the HP 4155B to test an NMOS device hooked up through the HP16058 Test Fixture as summarized in Table L3.1(a).

HP 4155B Connector	Represented Voltage	Connect To:
SMU1	V _S	source
SMU2	V _{DS}	drain
SMU3	V _{GS}	gate
SMU4	V _B	bulk

TABLE L3.1(a). HP 4155B Connections for MOS Device Curve Measurement

Using the hookup indicated in Table L3.1(a), use the following procedure to measure the I_D versus V_{DS}/V_{GS} curves (for V_{DS} ranging from 0V to 5V, and V_{GS} ranging from 0V to 10V, in steps of 1V, with V_B = -3V) and obtain a data plot for one of the NMOS transistors in your CD4007UB chip:

[The HP 4155A/B/C has two types of keys: "hard" keys, which are dedicated buttons on the front panel, and a column of "soft" keys, just to the right of the screen. In the procedure below, a $\boxed{\text{KEY}}$ is a hard key, and a $\boxed{\text{KEY}}$ is a soft key.]

- (1) CHAN to navigate to the "CHANNEL DEFINITION" screen. Name the channels according to Table L3.1(a) above. Be sure to set V_{DS} to VAR1 and V_{GS} to VAR2, which will allow you to sweep V_{DS} while stepping V_{GS} .
- (2) $\boxed{\text{MEAS}}$ to get to the "SWEEP SETUP" screen. Set the sweep parameters so that V_{DS} is swept from 0V to 5V (in steps of at most 100mV) and V_{GS} is swept from 0V to 10V in 1V steps. Be sure to ground V_S and set V_B to -3V.
- (3) DISPLAY to get to the "DISPLAY SETUP" screen. Here you should set the axes according to the type of characteristic you want to plot. For example, $I_d V_{DS}$ curves would be plotted with V_{DS} on the x-axis and I_D on the y-axis. Note that for the $I_D V_{GS}$ curves, you should set V_{DS} to be a CONST voltage while sweeping V_{GS} .
- (4) <u>GRAPH/LIST</u> to get the "GRAPHICS PLOT" window.
- (5) $|\underline{SINGLE}|$ to perform the measurement.

(6) SCALING, AUTOSCALING if necessary to view the whole plot.

Now, measure the slope in the linear region of the $V_{GS}=5V$ curve using a measurement line as follows:



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- (14) $\begin{array}{c} \text{LINE} \\ \text{OFF} \end{array}$ to turn on the line, which should be drawn between the two cursors you have positioned. The soft key should now read $\begin{array}{c} \text{LINE} \\ \text{ON} \end{array}$.
- (15) You can then now read the intercept and gradient values for the drawn line from the display. Be sure that grad mode is off.

From the slope just determined, calculate the value of r_{ds} in the linear region for this transistor with $V_{GS}=5$ V.

(b) With the same transistor-to-test fixture hookup as in (a), measure the I_D versus V_{GS} characteristic for values of V_B ranging from 0 to -5V in 1V increments (with $V_{DS} = 50$ mV), plot it, and determine the zero-bulk-bias threshold voltage for your NMOS device using the following procedure:

Now, determine the threshold voltage by locating the apparent point where the curve intersects the V_{GS} -axis (c.f., Fig. L3.1). Do this using the measurement line as described in part (a), being sure to place the measurement line along the steep part of the curve.



(c) Still with the same transistor-to-test-fixture hookups, measure the drain-to-source resistance r_{ds} (on a log scale) versus V_{GS} characteristic as follows:

- (1) $\square SPLAY$ to get to the "DISPLAY SETUP" page. This page defines the plot(s) to be measured when you hit $\square SINGLE$ later on. At this point, the page is setup to plot I_D (defined in the Y1-axis column) versus V_{GS} (defined in the X-axis column).
- (2) Move the pointer to the Y1-axis column and select "RDS" from the soft-keys as the Y1-axis name. "RDS" is a defined function (defined on the "CHANNELS: USER FUNCTION DEFINITION" page) that calculates the r_{ds} resistance for you from the I_D versus V_{GS} data that the HP 4155B actually measures. Switch to "LOG" scale for the Y1-axis and set the minimum and maximum scale values to 0 and 100000, respectively. Now, you have effectively set up the HP 4155B to measure the MOS small-signal resistance r_{ds} as a function of gate voltage $V_{GS}=V_C$.



(d) Repeat steps (a) through (c) for another MOS transistor on your CD4007UB chip. Keep track of which transistor is which. Call the first one M_1 and call the second one M_2 .

2. Gain-Controllable Amplifier

- (a) Hook up the circuit in Fig. PL3.1(b) and apply a 0.2Vpp, 10-kHz sinewave to the input of the circuit. Use your oscilloscope to measure the low frequency gain V_0/V_i and 3dB bandwidth of this amplifier for values of control voltage V_C ranging from 2V to 10V, in steps of 1V. Tabulate your data using the "measured" sections of Table LR3.2 in the *Results Sheet for Laboratory Exercises*, then plot the gain versus V_C and 3dB bandwidth versus V_C on separate graphs.
- (b) Did you see distortion for any of the *V*_C values? Explain.
- (c) [Note: You can do this part after the lab period, if necessary.] Extract values for K_n and V_{TN} from your part 1 measurements and use these to fill in the "calculated" portions of Table LR3.2 in the *Results Sheet for Laboratory Exercises*. Then plot the gain versus V_C and 3dB bandwidth versus V_C on the same graphs as your measured data, being sure to delineate which graph is which. Comment on any discrepancies between measured and calculated data.
- (d) Next, set the amplitude of the input sinewave to 5Vpp and the frequency to 10kHz. Print out a plot of the ensuing output waveform. Does the waveform look strange? Why? Now what is the gain of the amplifier? (Determine gain based on peak signals, whether they are sinusoidal or not.)

3. Bandwidth-Controlled (Unity-Gain) Filter

(a) Hook up the circuit in Fig. PL3.2(a) and apply a 0.2Vpp, 10-kHz sinewave to the input of the circuit. Use your oscilloscope to measure the low frequency gain V_o/V_i and 3dB

bandwidth of this amplifier for values of control voltage V_C ranging from 1V to 10V, in steps of 1V. Tabulate your data using the "measured" sections of Table LR3.3 in the *Results Sheet for Laboratory Exercises*, then plot the gain versus V_C and 3dB bandwidth versus V_C on separate graphs.

- (b) [Note: You can do this part after the lab period, if necessary.] Using your extracted values for K_n and V_{TN} from Part 2(b) above, fill in the "calculated" portions of Table LR3.3 in the *Results Sheet for Laboratory Exercises*. Then plot the gain versus V_C and 3dB bandwidth versus V_C on the same graphs as your measured data, being sure to delineate which graph is which. Comment on any discrepancies between measured and calculated data.
- (c) Next, set the amplitude of the input sinewave to 5Vpp and the frequency to 10kHz. Print out a plot of the ensuing output waveform. Does the waveform look better or worse than the waveform seen under a large input for the circuit in Part 2? Why?

Laboratory 3: Configurable Amplifiers Using Small-Signal MOS Resistors Results Sheet for Laboratory Exercises

NAME: _____ L

LAB SECTION:

1. Characterizing MOS Transistors

(a) Attach annotated HP 4155B plot of I_D vs. V_{DS}/V_{GS} curves for both M_1 and M_2 . Show all calculations on the plot.

 $r_{ds1}(\text{for } M_1 \text{ with } V_{GS1}=5\text{V}) =$

|--|

- (b) Attach annotated HP 4155B plot of I_D versus V_{GS} . Show all calculations on the plot.
 - $V_{t1}(\text{for } M_1) =$
 - $V_{t2}(\text{for } M_2) =$
- (c) Attach annotated HP 4155B plot of r_{ds} versus V_{GS} .

2. Gain-Controllable Amplifier

(a) Fill in the columns associated with the "measured" portions of Table LR3.2.

Attach the required annotated plots.

(b) Explain any distortion seen.

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(c) Fill in the columns associated with the "calculated" portions of Table LR3.2.

Plots your results as required on the same graph as the measured data.

V _C [V]	Gain, V _o /V _i		3dB_BW	
	2(a) Measured	2(b) Calculated	2(a) Measured	2(b) Calculated
2				
3				
4				
5				
6				
7				
8				
9				
10				

Table LR3.2. Gain-Configurable Amplifier Characteristics

(c) Attach an annotated plot of the output waveform.

Does the waveform look strange? Why?

Gain, $V_o/V_i =$

3. Bandwidth-Controlled (Unity-Gain) Filter

(a) Fill in the columns associated with the "measured" portions of Table LR3.3.

Attach the required annotated plots.

(d) Fill in the columns associated with the "calculated" portions of Table LR3.3.

Plots your results as required on the same graph as the measured data.

V _C [V]	Gain, V _o /V _i		3dB BW	
	3(a) Measured	3(b) Calculated	3(a) Measured	3(b) Calculated
2				
3				
4				
5				
6				
7				
8				
9				
10				

Table LR3.3. Bandwidth-Configurable Amplifier Characteristics

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(c) Does the waveform look better or worse than the waveform seen under a large input for the circuit in part 2? Why?

4. GENERAL QUESTIONS

Using the data obtained in Part 3(a) of the laboratory exercises, determine the percent mismatch in K_n and V_t between these two transistors. Percent mismatch can be determined using the following formula:

%Mismatch =
$$100 \times \frac{P_2 - P_1}{P_{avg}} = 2 \times 100 \times \frac{P_2 - P_1}{P_2 + P_1}$$
.

% Mismatch in $K_n =$

% Mismatch in V_t = _____